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By:

Date:

March 27, 2003

#1616
49 03
J. Carter

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Dieter Kantz et al.
Applic. No. : 09/826,594
Filed : April 5, 2001
Title : Test Configuration for the Functional Testing
of a Semiconductor Chip
Examiner : Ernest F. Karlsen
Group Art Unit : 2829

A M E N D M E N T

Hon. Commissioner of Patents and Trademarks,
Washington, D. C. 20231

S i r :

Responsive to the Office action dated February 27, 2003 kindly
amend the above-identified application as follows:

In the Claims:

Add the following new claims:

Claim 23(new). The test configuration according to claim 20,
wherein said semiconductor chip has a functional unit for a

04/07/2003 HAHMED1 00000076 09826594

01 FC:1202

162.00 DP